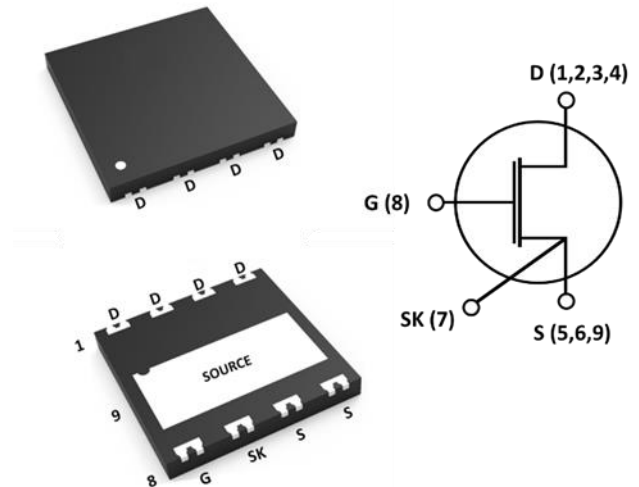


# NW6516ED1

## 650 V E-mode GaN Transistor

### Features

- 650 V enhancement mode GaN power transistor
- GaN-on-Si technology
- DFN 8x8 package
- Typical  $R_{DS(on)} = 165 \text{ m}\Omega$
- $I_{DS \text{ max,DC}} = 10 \text{ A}$
- Simple gate drive 0 V to 6 V
- High switching frequency (> 1 MHz)
- Reverse conduction capability
- Zero reverse recovery loss
- Kelvin Source for optimized gate drive
- CDM 1 kV



### Applications

- PD chargers
- Power Adapters
- Power Factor Correctors
- High density power conversion
- High efficiency power conversion

### Description

The NW6516ED1 is an enhancement mode GaN transistor designed for large power density and high switching frequency. The excellent properties of GaN enable high-frequency switching at high currents and voltages, leading to high efficiency and reliable power switching.

### Pin Description

Pin No.	Pin Name	Description
1,2,3,4	D	Drain
5,6,9	S	Source
7	KS	Kelvin Source
8	G	Gate

## Absolute Maximum Ratings

$T_J = 25^\circ\text{C}$  except as noted. Exceeding the maximum ratings may damage the device.

Parameter	Symbol	Value	Unit
Drain-to-Source Voltage	$V_{DS}$	650	V
Drain-to-Source Voltage – transient (Note 1)	$V_{DS}$ (transient)	750	V
Gate-to-Source Voltage	$V_{GS}$	-10 to +7	V
Gate-to-Source Voltage – transient (Note 1)	$V_{GS}$ (transient)	-20 to 10	V
Continuous Drain Current ( $T_{case} = 25^\circ\text{C}$ )	$I_{DS}$	10	A
Pulsed Drain Current ( $T_{case} = 25^\circ\text{C}$ ) (Pulse width 10us, $V_{GS} = 6\text{ V}$ ) (Note 2)	$I_{DS, Pulse}$	17	A
Pulsed Drain Current ( $T_{case} = 150^\circ\text{C}$ ) (Pulse width 10us, $V_{GS} = 6\text{ V}$ ) (Note 2)	$I_{DS, Pulse}$	7.5	A
Power Dissipation	$P_{tot}$	107	W
Operating Junction Temperature	$T_J$	-55 to +150	$^\circ\text{C}$
Storage Temperature Range	$T_S$	-55 to +150	$^\circ\text{C}$

Note 1: for pulses  $\leq 100\text{us}$

Note 2: Defined by product design and characterization. Value is not tested to full current in production.

## Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal Resistance Junction-to-Case – (bottom side)	$R_{TH,J-C}$	1.16	$^\circ\text{C/W}$
Thermal Resistance Junction-to-ambient (Note 3)	$R_{TH,J-A}$	32.9	$^\circ\text{C/W}$

Note 3: Based on a 4-layer, 1.6 mm-thick PCB. The copper thickness of the external layer is 2 oz. while the buried layers are 1 oz. thick. PCB in a horizontal position without air stream cooling.

## Electrical Characteristics

### Static Characteristics

Parameters	Symbol	Min	Typ	Max	Unit	Condition
Drain-to-Source On Resistance	$R_{DS(on)}$	-	165	260	m $\Omega$	$I_{DS} = 3.5 \text{ A}, V_{GS} = 6 \text{ V}, T_J = 25 \text{ }^\circ\text{C}$
		-	370	-	m $\Omega$	$I_{DS} = 3.5 \text{ A}, V_{GS} = 6 \text{ V}, T_J = 150 \text{ }^\circ\text{C}$
Gate-to-Source Threshold Voltage	$V_{GS(th)}$	1.1	1.6	2.6	V	$I_{DS} = 5.25 \text{ mA}, T_J = 25 \text{ }^\circ\text{C}$
		-	1.5	-	V	$I_{DS} = 5.25 \text{ mA}, T_J = 150 \text{ }^\circ\text{C}$
Gate-to-Source Current	$I_{GS}$	-	225	-	$\mu\text{A}$	$V_{GS} = 6 \text{ V}, T_J = 25 \text{ }^\circ\text{C}$
Drain-to-Source Leakage Current	$I_{DSS}$	-	1	50	$\mu\text{A}$	$V_{DS} = 650 \text{ V}, T_J = 25 \text{ }^\circ\text{C}$
		-	10	-	$\mu\text{A}$	$V_{DS} = 650 \text{ V}, T_J = 150 \text{ }^\circ\text{C}$
Internal Gate Resistance	$R_G$	-	1.6	-	$\Omega$	$f = 5 \text{ MHz}; \text{ open drain}$

### Dynamic Characteristics

Input Capacitance	$C_{ISS}$	-	83	-	pF	$V_{DS} = 400 \text{ V}, V_{GS} = 0 \text{ V}, f = 100 \text{ kHz}$
Output Capacitance	$C_{OSS}$	-	34	-	pF	
Reverse Transfer Capacitance	$C_{RSS}$	-	0.3	-	pF	
Effective Output Capacitance, Energy-Related (Note 4)	$C_{O(ER)}$	-	46	-	pF	$V_{DS} = 0 \text{ V to } 400 \text{ V}, V_{GS} = 0 \text{ V}$
Effective Output Capacitance, Time-Related (Note 5)	$C_{O(TR)}$	-	61.2	-	pF	
Output Charge	$Q_{OSS}$	-	24.5	-	nC	$V_{DS} = 0 \text{ V to } 400 \text{ V}$
Turn-On Delay	$t_{D(on)}$	-	3.5	-	ns	$V_{DD} = 400 \text{ V}, V_{GS} = 0 \text{ to } 6 \text{ V}, I_{DS} = 6 \text{ A}, R_{G(on)} = 10 \text{ } \Omega, R_{G(off)} = 2.2 \text{ } \Omega$ (see Figures 14, 15)
Rise Time	$t_R$	-	6.8	-	ns	
Turn-Off Delay	$t_{D(off)}$	-	2.1	-	ns	
Fall Time	$t_F$	-	5	-	ns	

Switching Energy during Turn-on	$E_{on}$	-	16.8	-	$\mu$ J	
Switching Energy during Turn-off	$E_{off}$	-	7.2	-	$\mu$ J	
Output Capacitance Stored Energy	$E_{OSS}$	-	3.7	-	$\mu$ J	$V_{DS} = 400$ V

Note 4:  $C_{O(ER)}$  is a fixed capacitance that would give the same stored energy as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 V to the stated  $V_{DS}$ .

Note 5:  $C_{O(TR)}$  is a fixed capacitance that would give the same charging time as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 V to the stated  $V_{DS}$ .

### Gate Charge Characteristics

Total Gate Charge	$Q_G$	-	2.21	-	nC	$V_{GS} = 0$ to 6 V, $V_{DS} = 0$ to 400 V, $I_{DS} = 5$ A
Gate-to-Source Charge	$Q_{GS}$	-	0.72	-	nC	
Gate-to-Drain Charge	$Q_{GD}$	-	0.28	-	nC	
Gate Plateau Voltage	$V_{Plat}$	-	2.11	-	V	$V_{DS} = 400$ V, $I_{DS} = 5$ A

### Reverse Conduction Characteristics

Source-Drain Reverse Voltage	$V_{SD}$	-	2.4	-	V	$V_{GS} = 0$ V, $I_{SD} = 2$ A
Reverse Recovery Charge	$Q_{rr}$	-	0	-	nC	
Reverse Recovery Time	$t_{rr}$	-	0	-	ns	

### Electrostatic Discharge (ESD) Classification

Parameters	Symbol	Notes
Charge Device Model	CDM	$\geq 1$ kV

### Electrical Performance Graphs

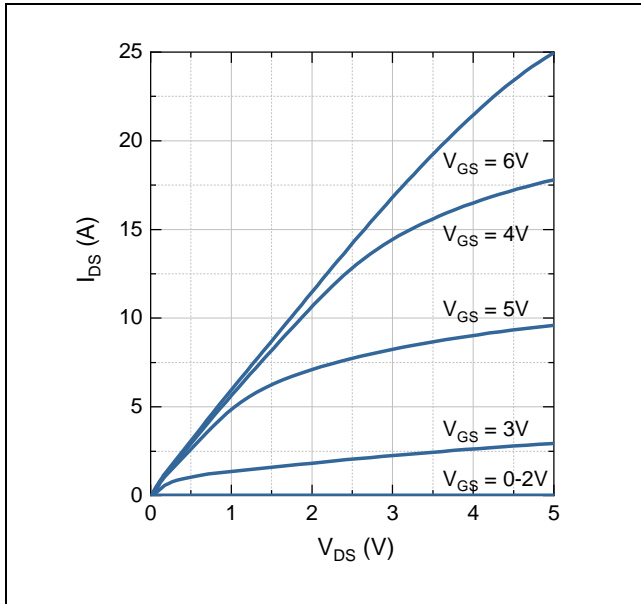


Figure 1: Typical pulsed  $I_{DS}$  vs.  $V_{DS}$  Output Characteristics at  $T_J = 25\text{ }^\circ\text{C}$

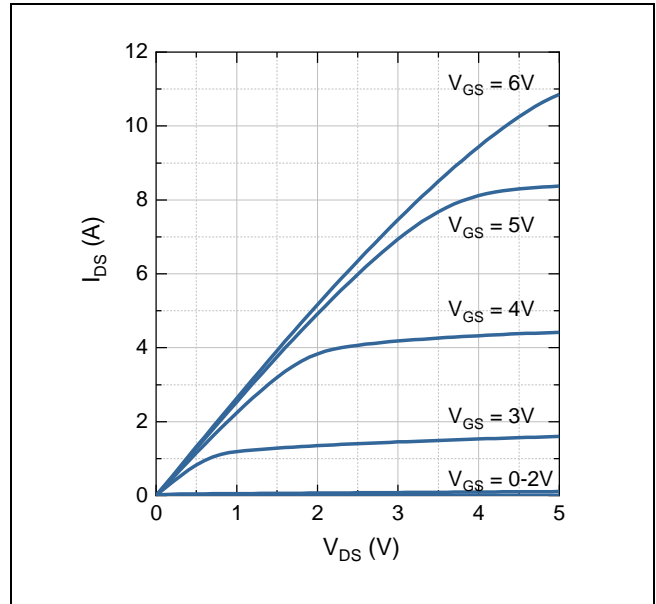


Figure 2: Typical pulsed  $I_{DS}$  vs.  $V_{DS}$  Output Characteristics at  $T_J = 150\text{ }^\circ\text{C}$

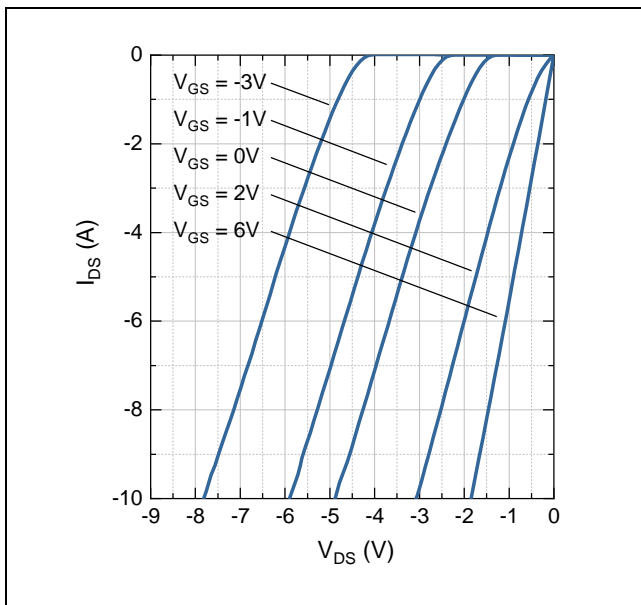


Figure 3: Typical Reverse Conduction Characteristics at  $T_J = 25\text{ }^\circ\text{C}$

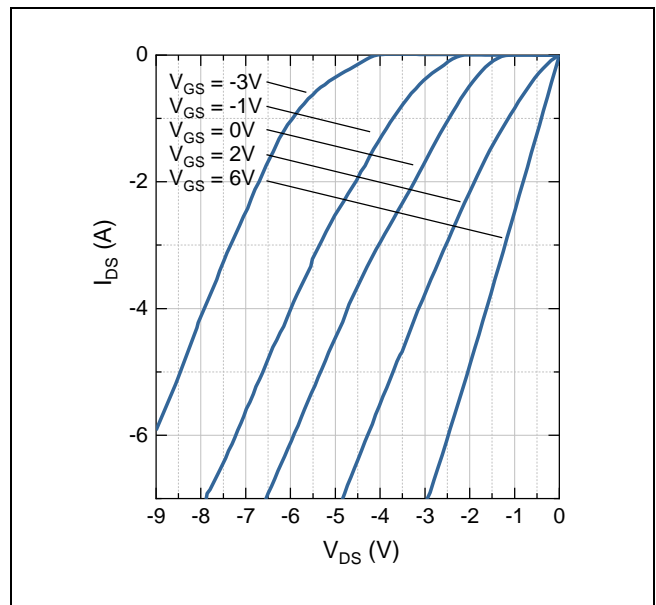


Figure 4: Typical Reverse Conduction Characteristics at  $T_J = 150\text{ }^\circ\text{C}$

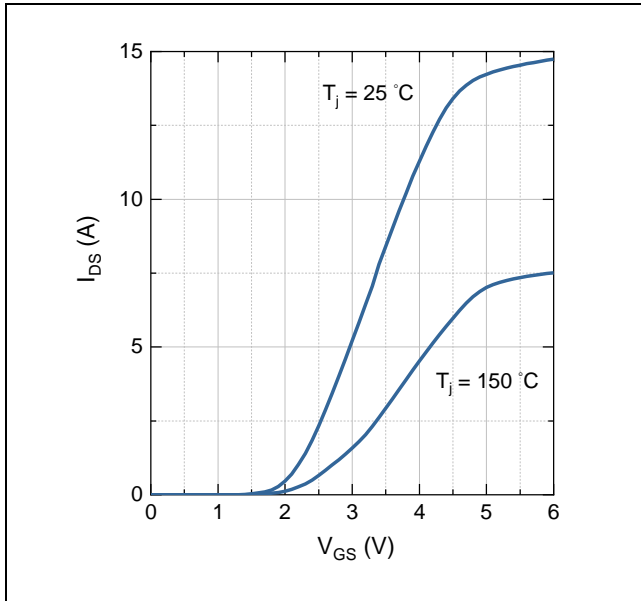


Figure 5: Typical  $I_{DS}$  vs.  $V_{GS}$  at  $T_J = 25\text{ }^\circ\text{C}$  and  $T_J = 150\text{ }^\circ\text{C}$  for  $V_{DS} = 3\text{ V}$

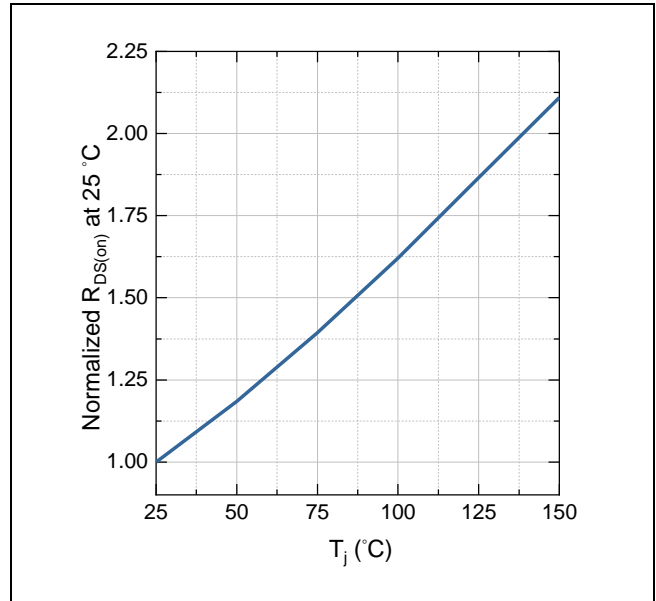


Figure 6: Normalized  $R_{DS(on)}$  as a function of  $T_J$

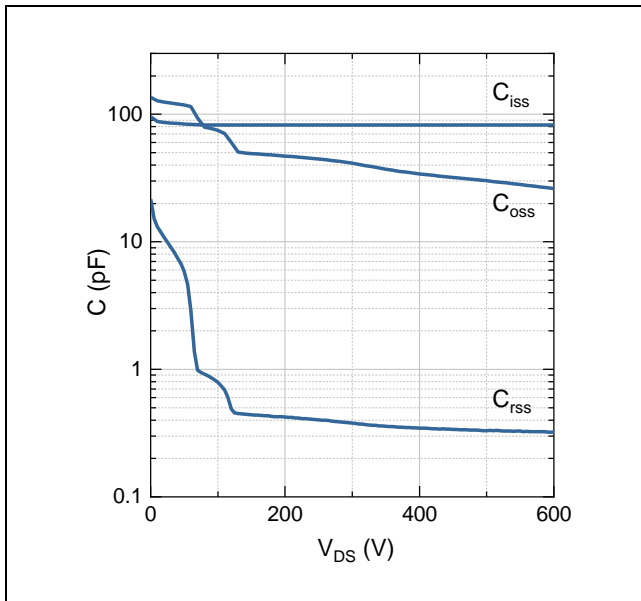


Figure 7: Typical  $C_{iss}$ ,  $C_{oss}$ ,  $C_{rss}$  vs.  $V_{DS}$

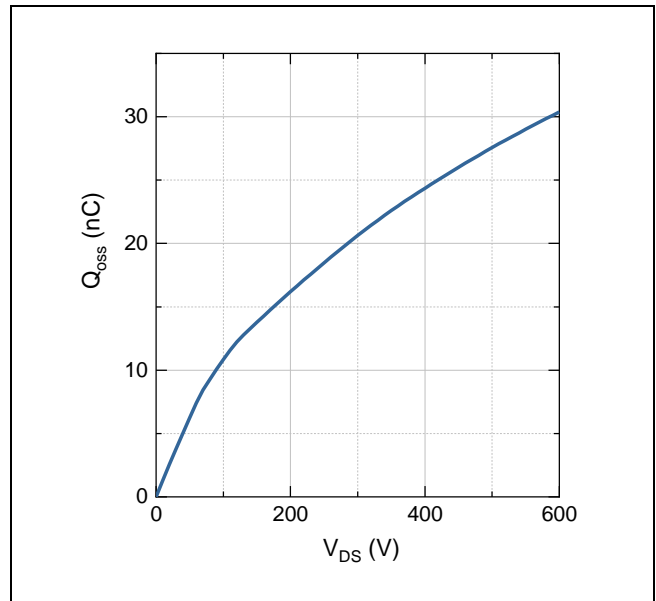


Figure 8: Typical charge stored in  $C_{oss}$

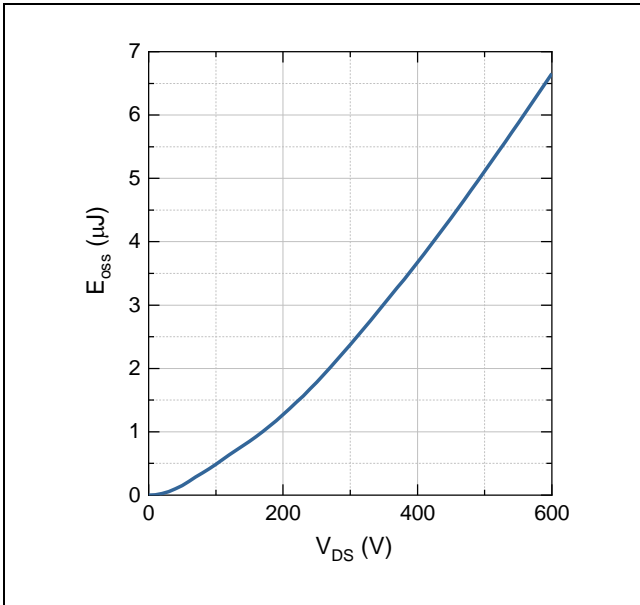


Figure 9: Typical energy stored in C<sub>oss</sub>

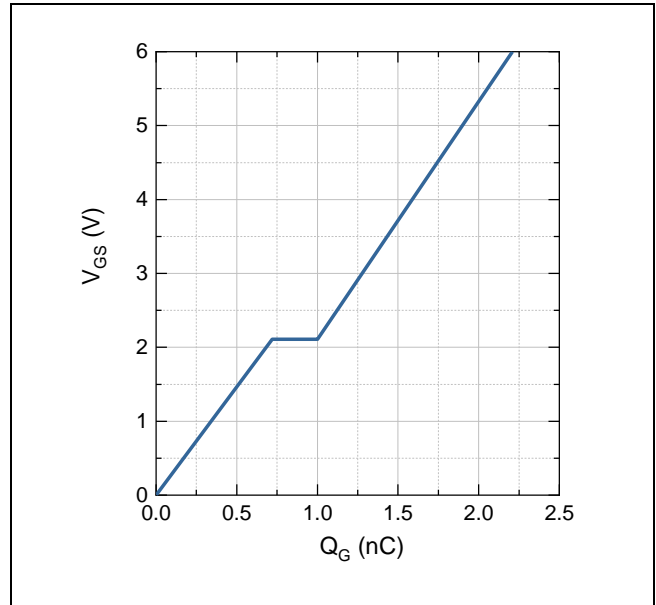


Figure 10: Typical V<sub>GS</sub> vs. Q<sub>G</sub> at V<sub>DS</sub> = 400 V

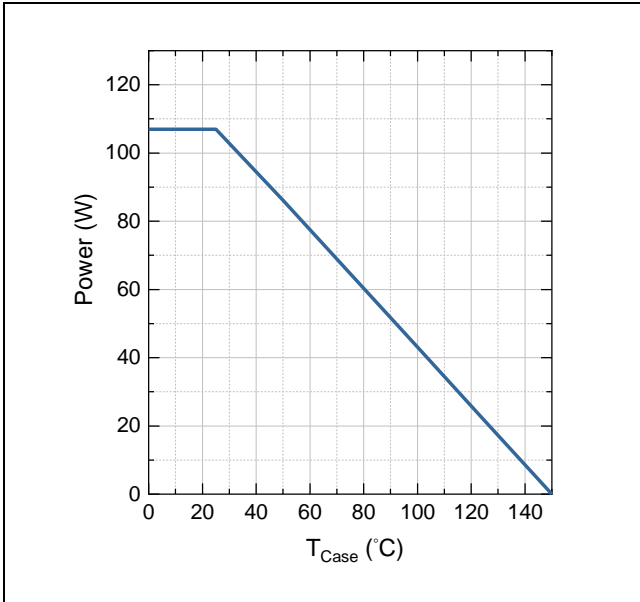


Figure 11: Power Derating vs. T<sub>case</sub>

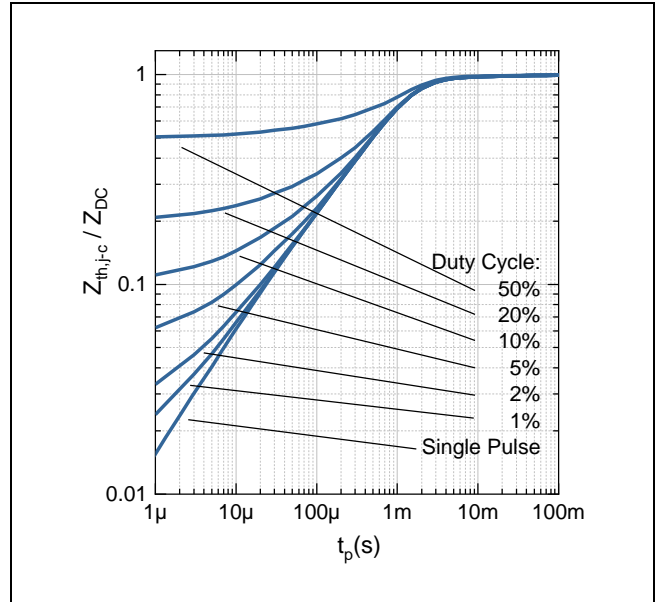
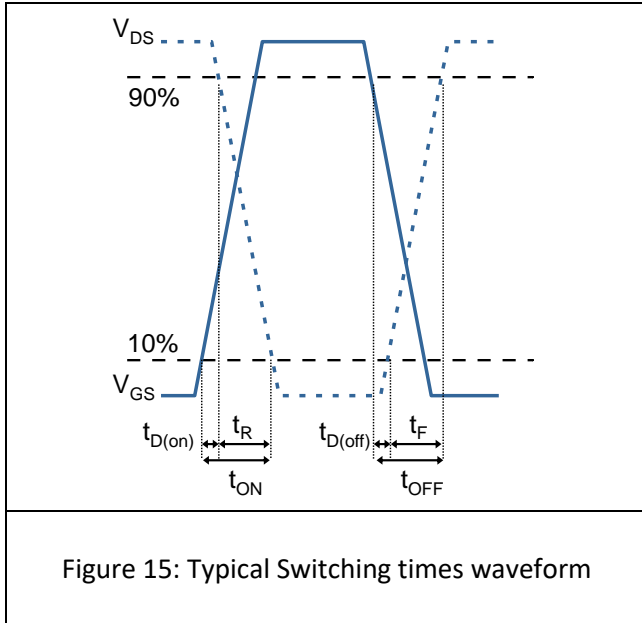
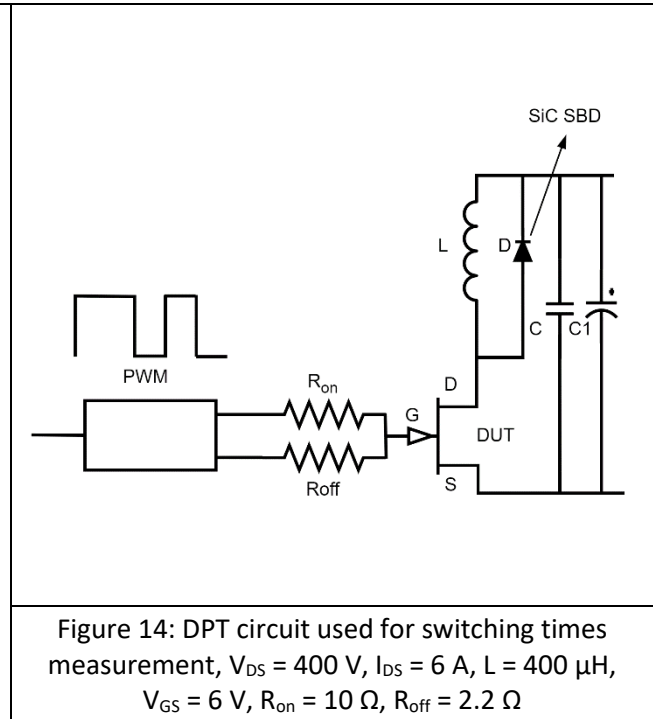
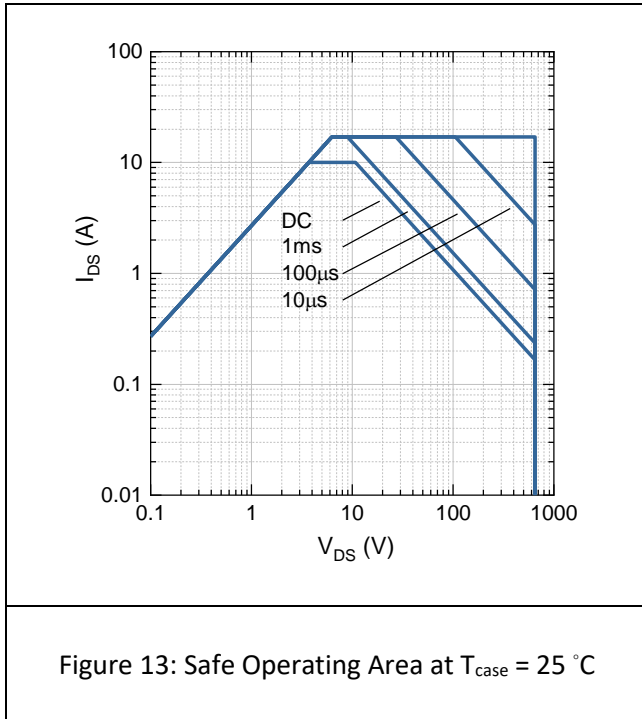
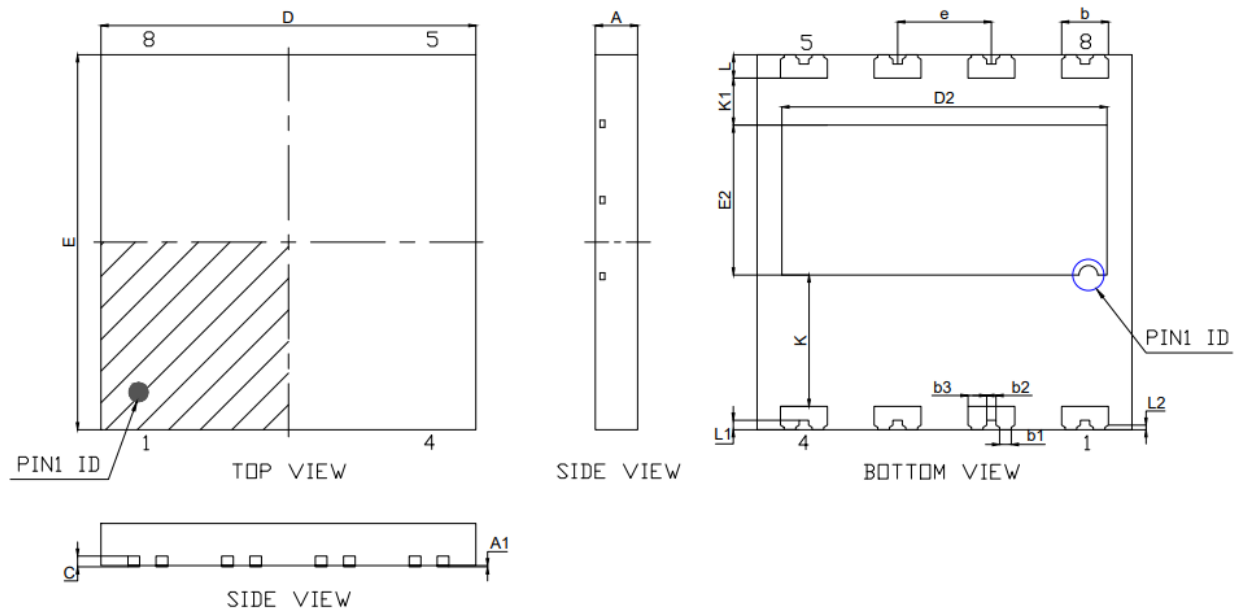


Figure 12: Transient Thermal Impedance





## Package Information



SYMBLE	MILLIMETER			SYMBLE	MILLIMETER		
	MIN	NOM	MAX		MIN	NOM	MAX
A	0.80	0.90	1.00	e	2.00BSC		
A1	0	0.02	0.05	E	7.90	8.00	8.10
b	0.95	1.00	1.05	E2	3.10	3.20	3.30
b1	0.25REF			L	0.40	0.50	0.60
b2	0.20REF			L1	0.20REF		
b3	0.35	0.40	0.45	L2	0.10REF		
c	0.203REF			K	2.80REF		
D	7.90	8.00	8.10	K1	1.00REF		
D2	6.84	6.94	7.04				

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